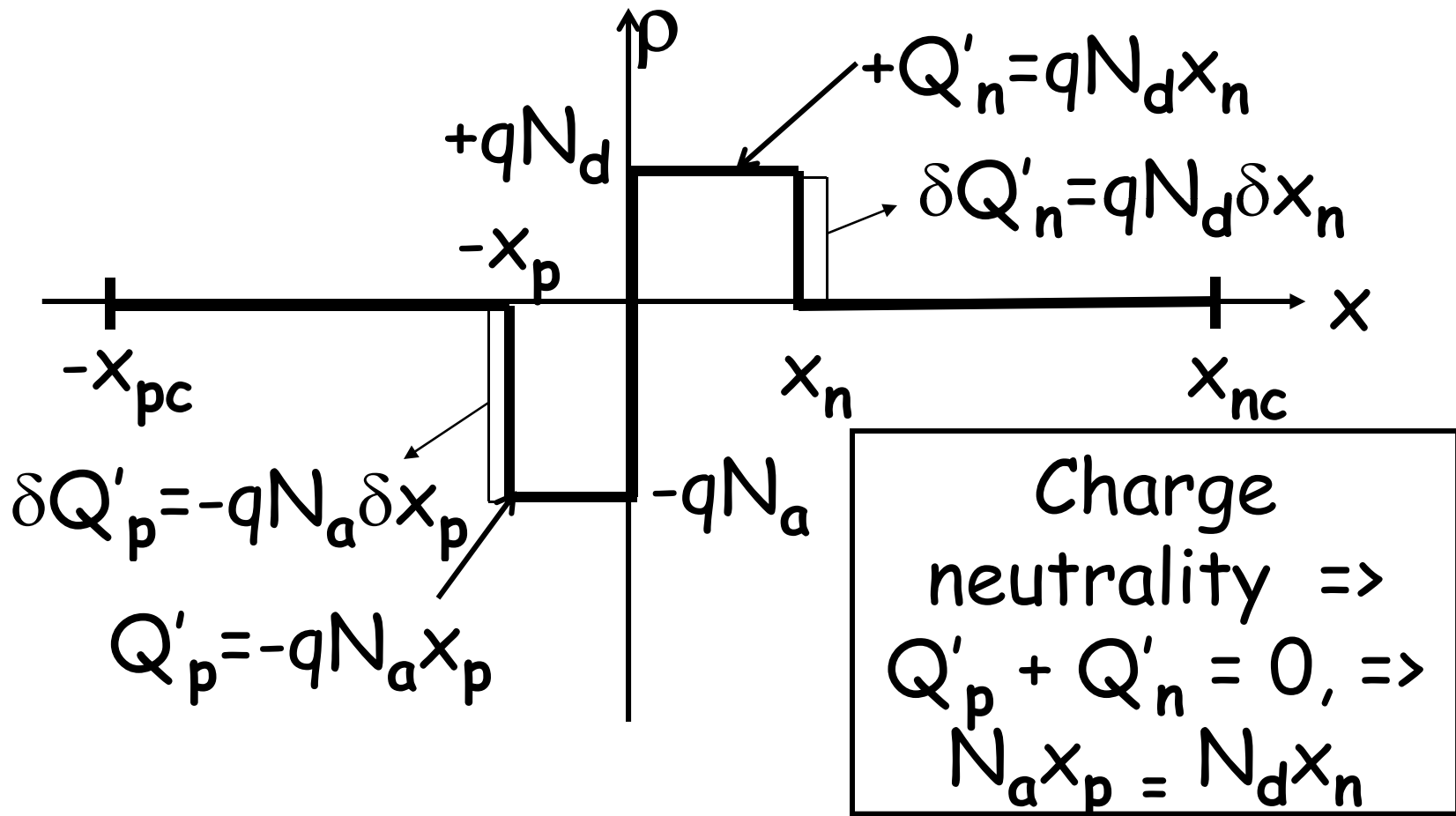


Lecture 07  
EE 2303/001-Electronics I  
February 11, 2009

Professor Ronald L. Carter  
ronc@uta.edu  
<http://www.uta.edu/ronc/>

# Junction C (cont.)

$$\delta Q_j = \delta Q'_n A$$



# Junction Depletion Capacitance

- The C-V model for a step junction is

$$C_j = C_{j0} \left[ 1 - \frac{V_a}{V_{bi}} \right]^{-\frac{1}{2}}, \quad V_{bi} = V_t \ln \left( \frac{N_a N_d}{n_i^2} \right)$$

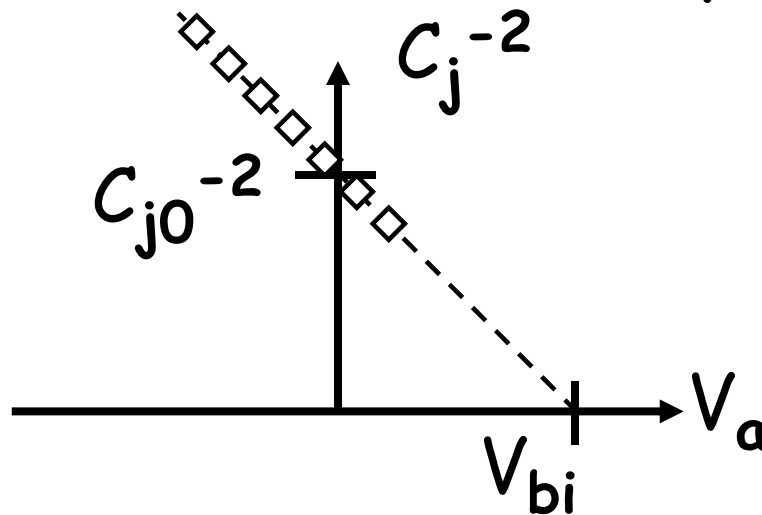
$$C_{j0} = A \sqrt{\frac{\epsilon q N_{\text{eff}}}{2 V_{bi}}} = \epsilon \frac{A}{W_{\text{depl}}}, \quad \epsilon = \epsilon_r \epsilon_0$$

$$\epsilon_{r,\text{Si}} = 11.7, \quad \epsilon_0 = 8.85 \times 10^{-14} \text{ Fd/cm}$$

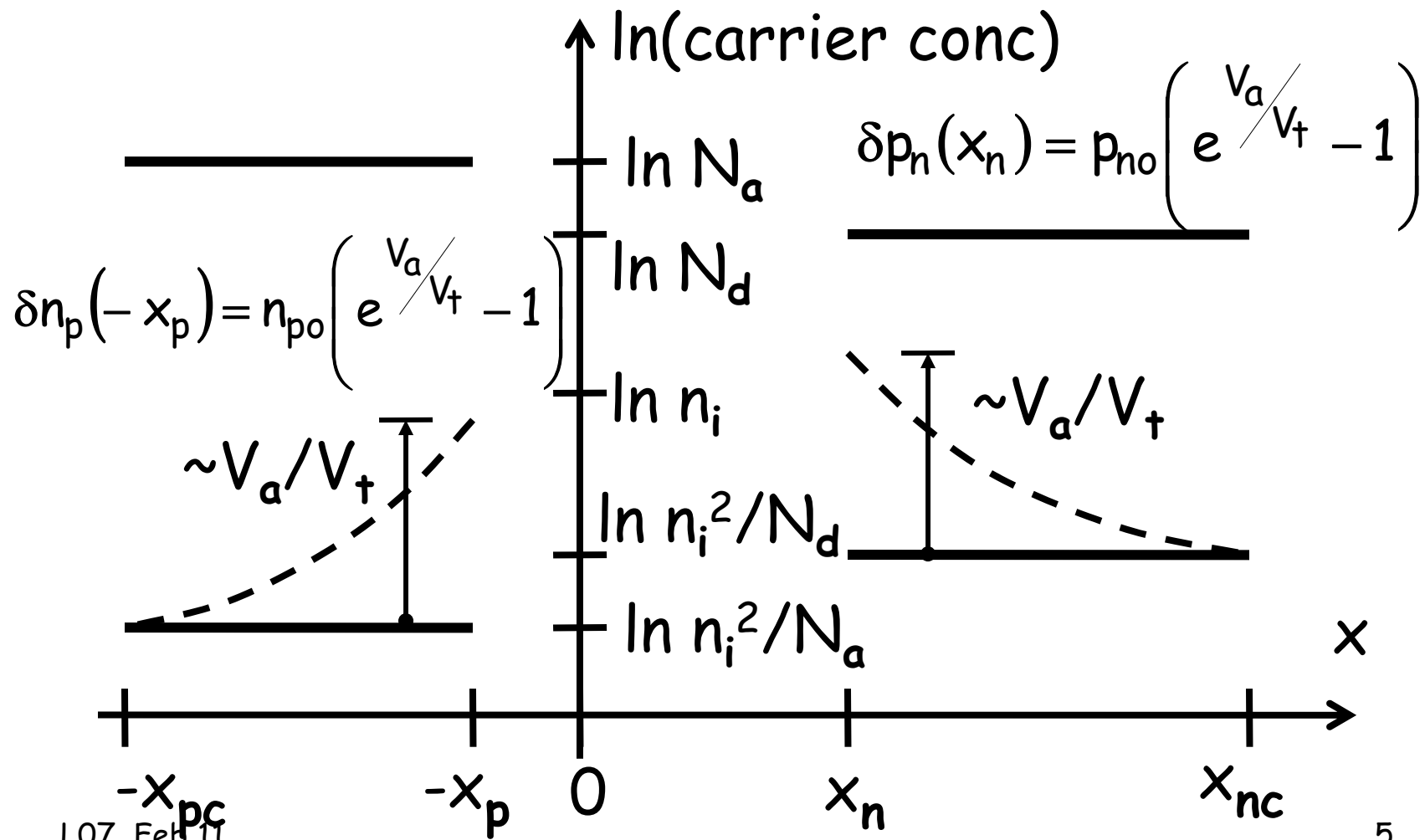
$$q = 1.602 \times 10^{-19} \text{ Coul.}, \quad V_t = 25.852 \text{ mV}$$

# Junction C (cont.)

- If one plots  $[C_j]^{-2}$  vs.  $V_a$   
Slope =  $-[(C_{j0})^2 V_{bi}]^{-1}$   
vertical axis intercept =  $[C_{j0}]^{-2}$   
horizontal axis intercept =  $V_{bi}$



# Carrier Injection and diff.



# Ideal diode equation

- $I = I_s [\exp(V_a/nV_t) - 1]$ ,  $I_s = I_{sn} + I_{sp}$

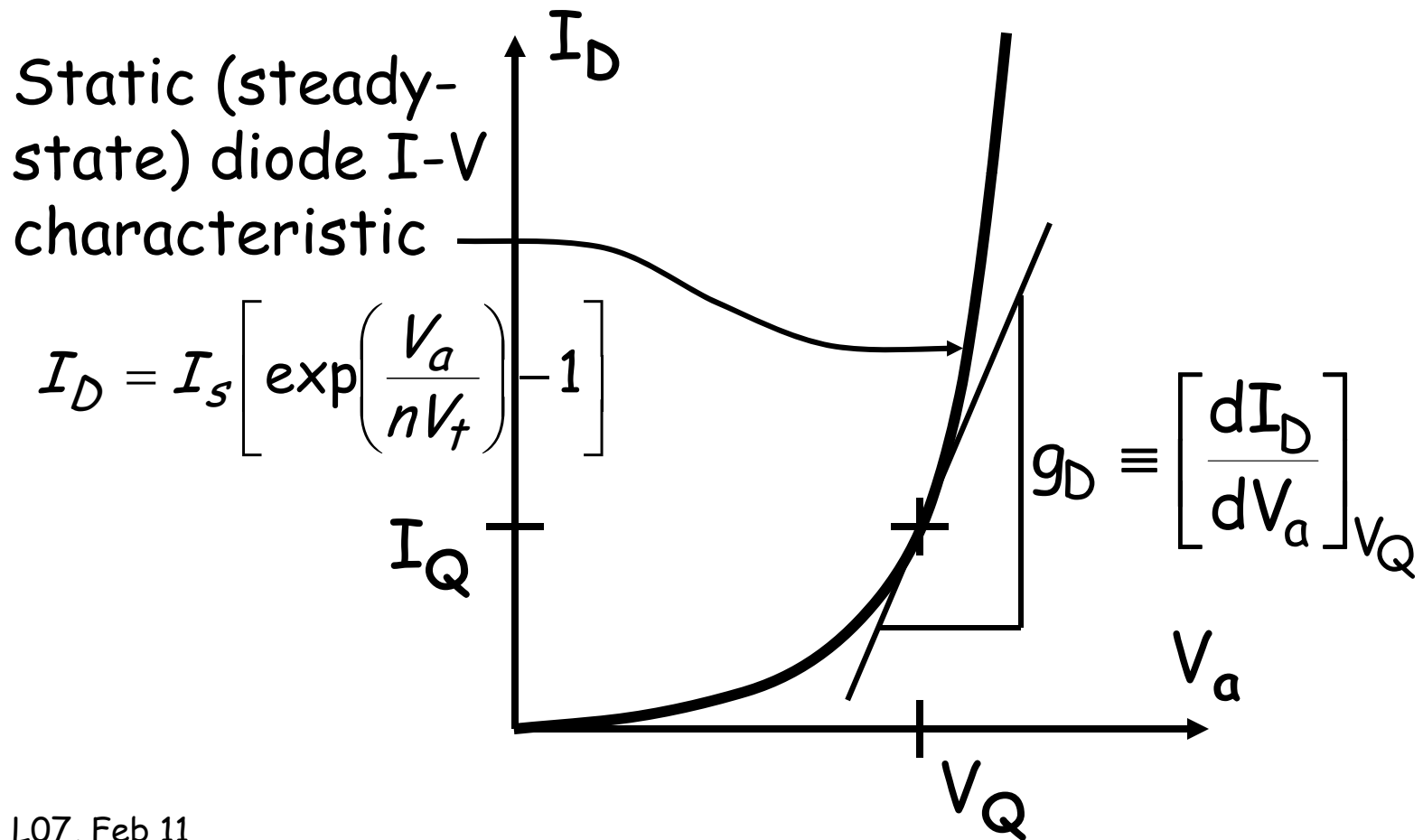
Long diode:  $W_n \gg L_p$ , or  $W_p \gg L_n$

$$I_{sn} = qn_i^2 A \frac{D_n}{N_a L_n}, \text{ and } I_{sp} = qn_i^2 A \frac{D_p}{N_d L_p}$$

Short diode:  $W_n \ll L_p$ , or  $W_p \ll L_n$

$$I_{sn} = qn_i^2 A \frac{D_n}{N_a W_p}, \text{ and } I_{sp} = qn_i^2 A \frac{D_p}{N_d W_n}$$

# Diffnt'l, one-sided diode conductance



# Diffnt'l, one-sided diode cond. (cont.)

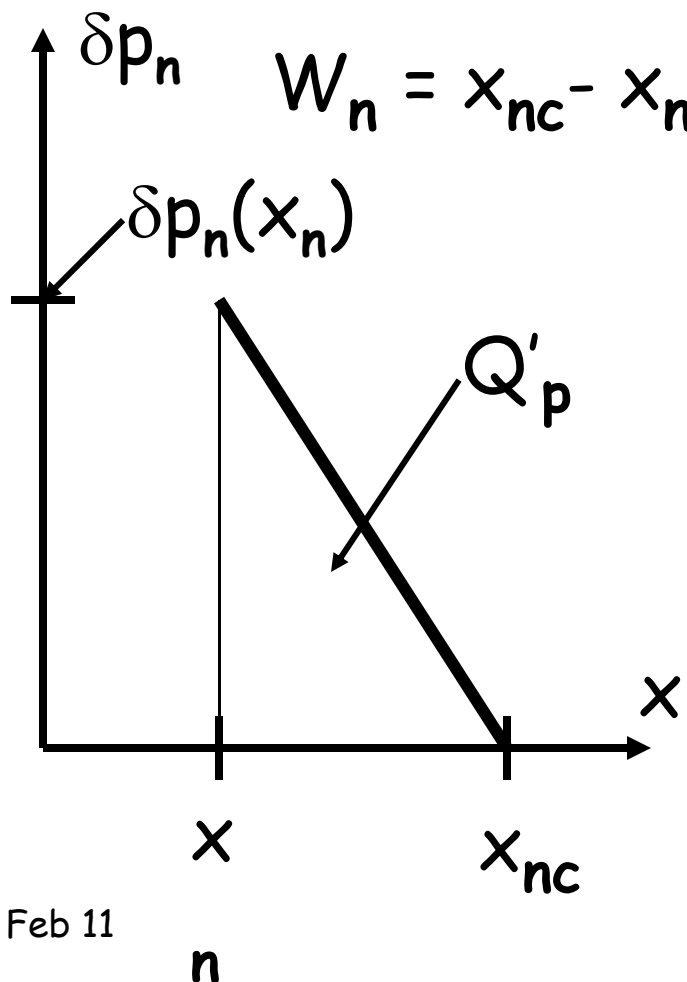
$$I_D = JA = J_s A [\exp(V_a/nV_t) - 1] = I_s [\exp(V_a/nV_t) - 1]$$

$$g_d(V_Q) = \left[ \frac{dI_D}{dV_a} \right]_{V_Q} = \frac{I_s \exp(V_Q/nV_t)}{V_t}. \text{ If } V_a > V_t,$$

$$\text{then } g_d(V_Q) = \frac{I_{DQ}}{nV_t}, \text{ where } I_{DQ} = I_D(V_Q).$$

$$\text{The diode resistance, } r_d(V_Q) = \frac{1}{g_d} = \frac{nV_t}{I_{DQ}}$$

# Charge distr in a (1-sided) short diode

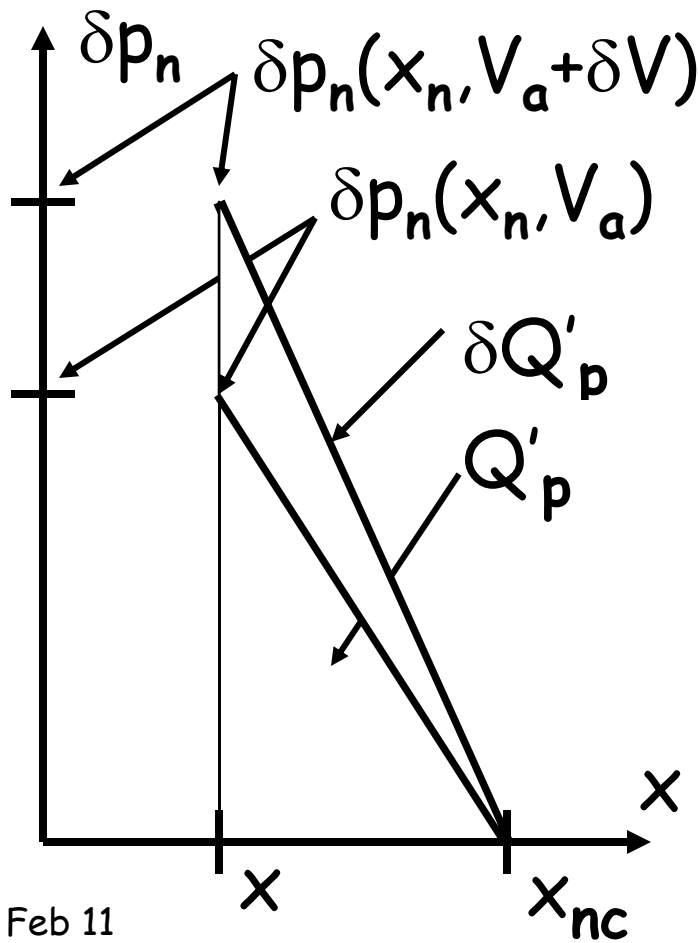


- Assume  $N_d \ll N_a$
- The sinh (see L12) excess minority carrier distribution becomes linear for  $W_n \ll L_p$

$$\delta p_n(x_n) = p_{n0} \exp(V_a/V_t)$$

- Total chg =  $Q'_p =$   
 $Q'_p = q \delta p_n(x_n) W_n / 2$

# Charge distr in a 1-sided short diode



- Assume Quasi-static charge distributions
- $Q'_p = Q'_p = q\delta p_n(x_n)W_n/2$
- $d\delta p_n(x_n) = (W/2)^* \{ \delta p_n(x_n, V_a + \delta V) - \delta p_n(x_n, V_a) \}$

# Cap. of a (1-sided) short diode (cont.)

$Q_p = Q'_p A$ ,  $A =$  diode area. Define  $C_d \equiv \frac{dQ_p}{dV_a} =$

$$\frac{d}{dV_a} \left( \frac{qA\delta p_n(x_n)W_n}{2} \right) = \frac{d}{dV_a} \left( \frac{qAp_{n0}W_n}{2} \exp d(V_a/V_t) \right)$$

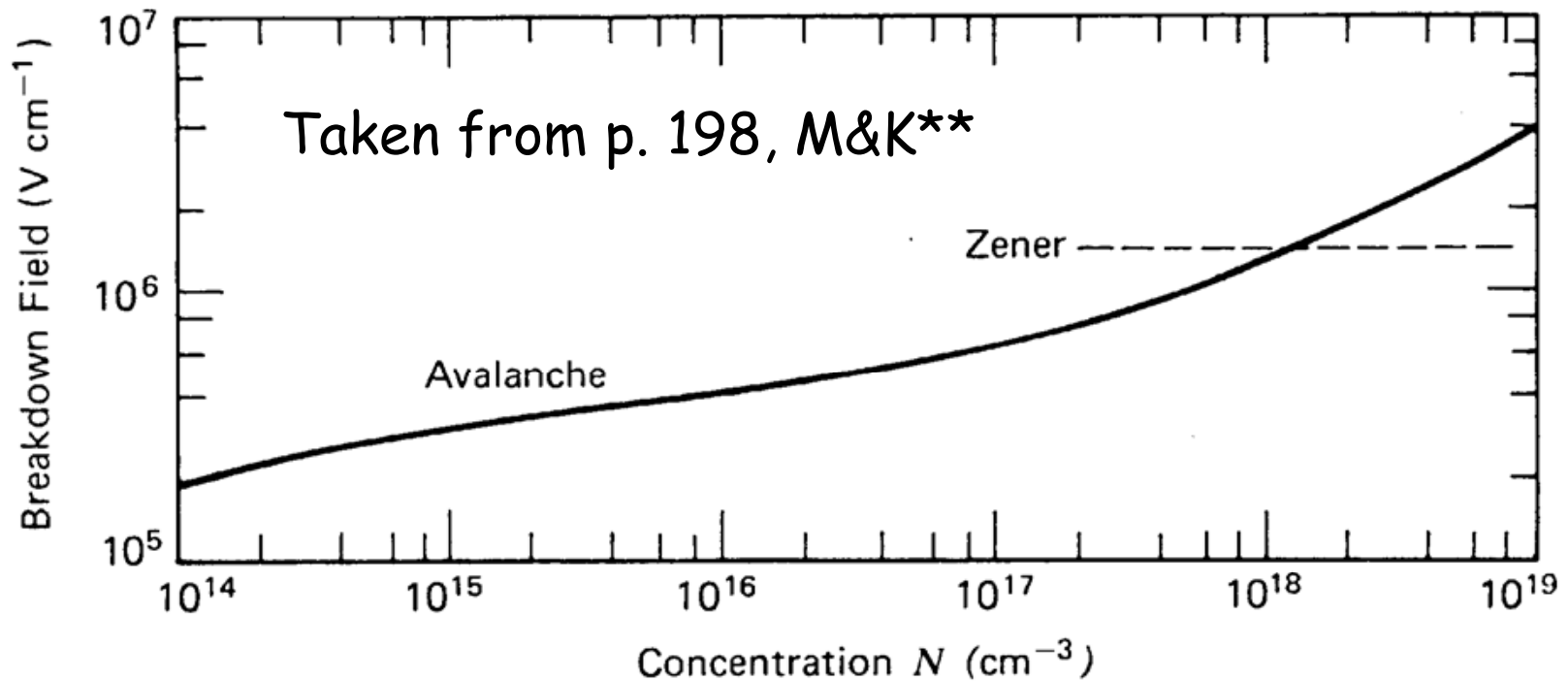
When  $V_a > V_t$ ,  $C_d(V_Q) = \frac{I_{DQ}}{V_t} \frac{W_n^2}{2D_p} \equiv \frac{I_{DQ}}{V_t} \tau_{transit}$ .

So,  $r_d(V_Q)C_d(V_Q) = \tau_{transit} \equiv \int_{x_n}^{x_{nc}} q \frac{\delta p_n}{J_p} dx = \frac{W_n^2}{2D_p}$

# Reverse bias junction breakdown

- Avalanche breakdown
  - Electric field accelerates electrons to sufficient energy to initiate multiplication of impact ionization of valence bonding electrons
  - field dependence shown on next slide
- Heavily doped narrow junction will allow tunneling - see Neamen\*, p. 274
  - Zener breakdown

# $E_{\text{crit}}$ for reverse breakdown (M&K\*\*)



**Figure 4.12** The critical electric fields for avalanche and Zener breakdown in silicon as functions of dopant concentration.<sup>1,2,3</sup>

# Reverse bias junction breakdown

- Assume  $-V_a \equiv V_R \gg V_{bi}$ , so  $V_{bi} - V_a \rightarrow V_R$

- Since  $E_{\max} = 2(V_{bi} - V_a)/W$ ,

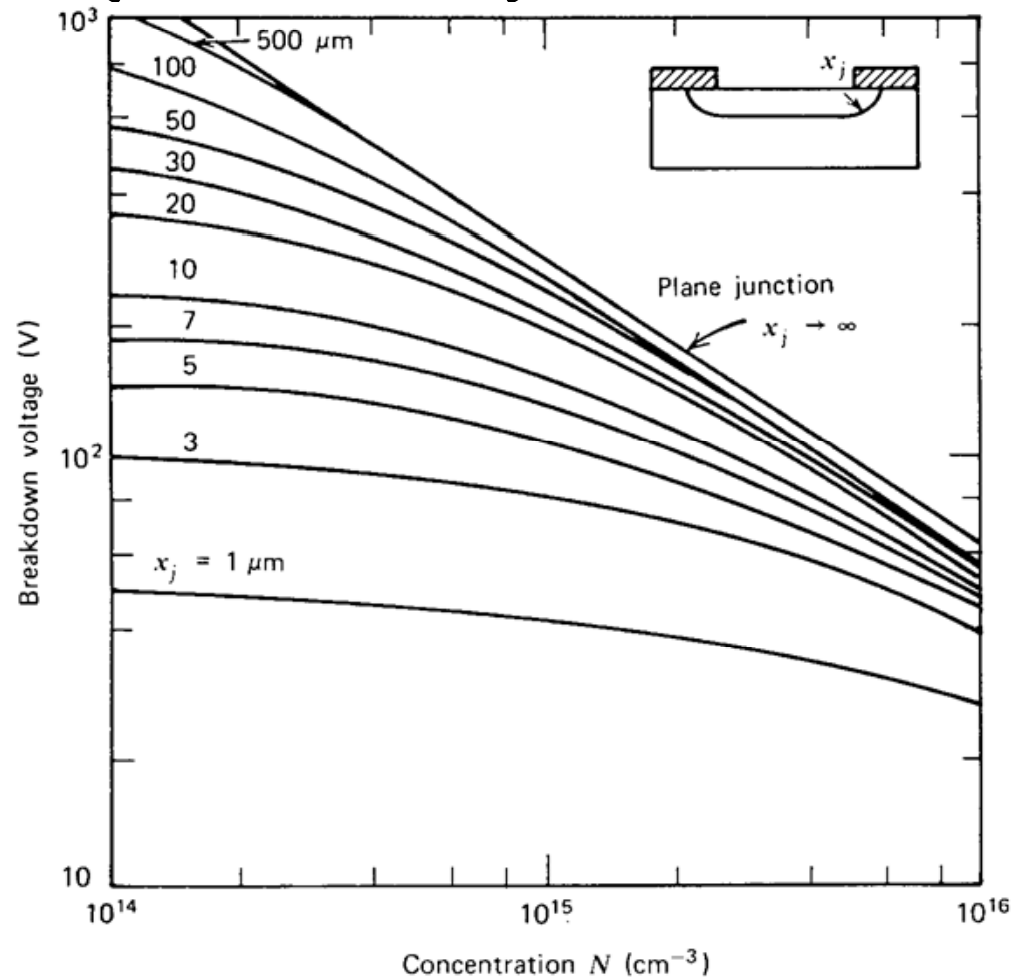
when  $E_{\max} = E_{\text{crit}}$

$$BV = \varepsilon (E_{\text{crit}})^2 / (2qN^-)$$

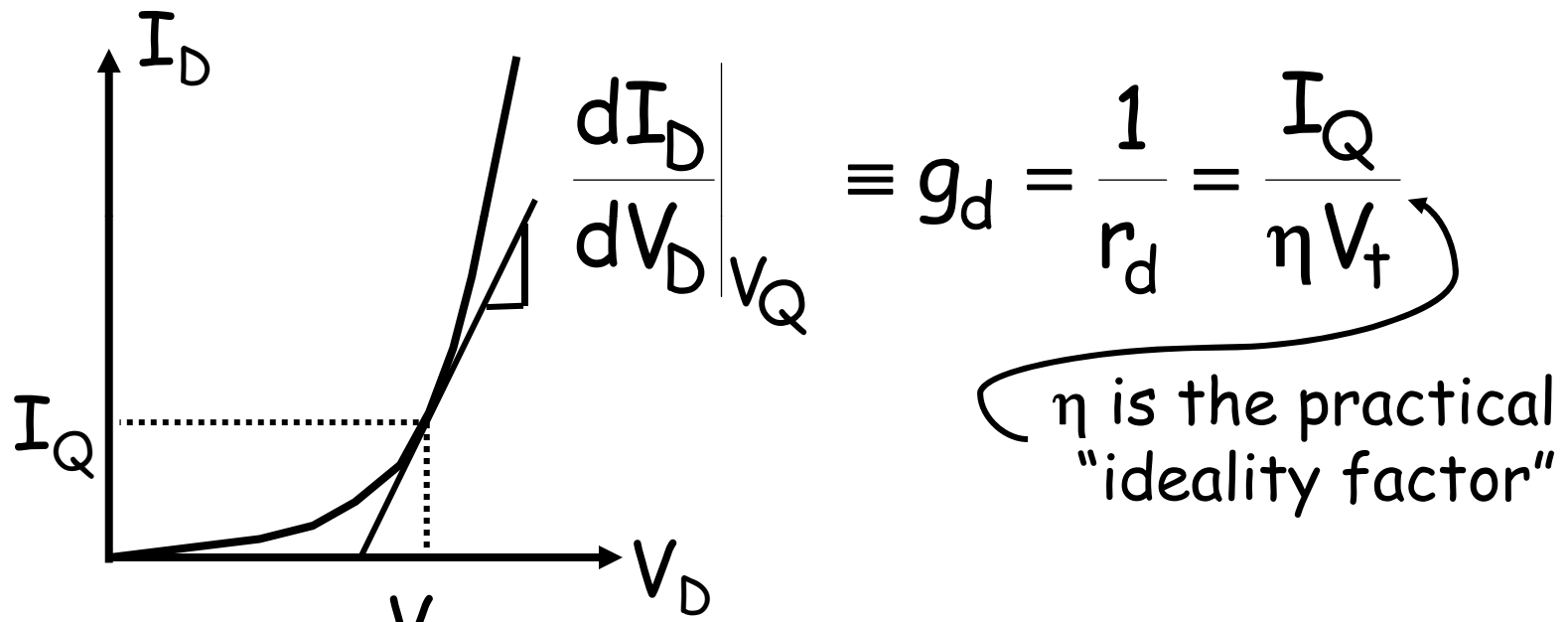
# BV for reverse breakdown (M&K\*\*)

Taken from  
Figure 4.13,  
p. 198, M&K\*\*

Breakdown  
voltage of a  
one-sided, plan,  
silicon step  
junction showing  
the effect of  
junction  
curvature. 4,5



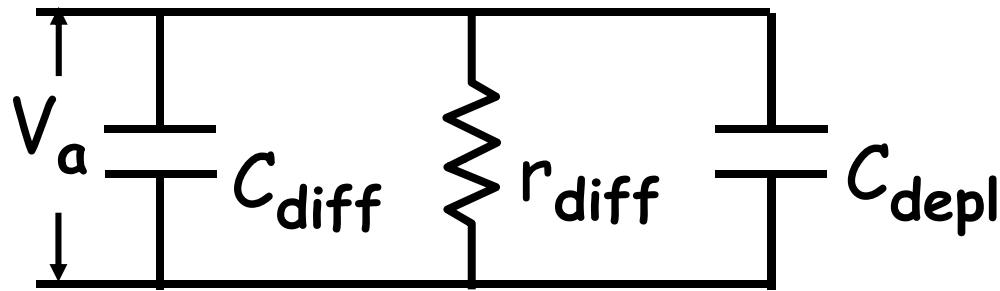
# Diode equivalent circuit (small sig)



$$r_d C_d = \tau, \quad (\tau_{tr} \text{ for short, } \tau_{min} \text{ for long})$$

$$C_{diffusion} = \frac{\tau I_Q}{\eta V_t}, \quad r_{diff} = \frac{\eta V_t}{I_Q}$$

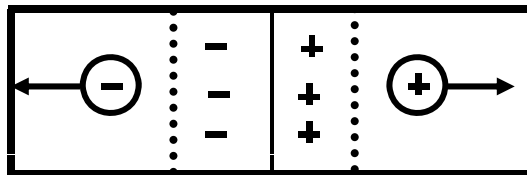
# Small-signal eq circuit



$C_{diff}$  and  $C_{depl}$  are both charged by

$$V_a = V_Q$$

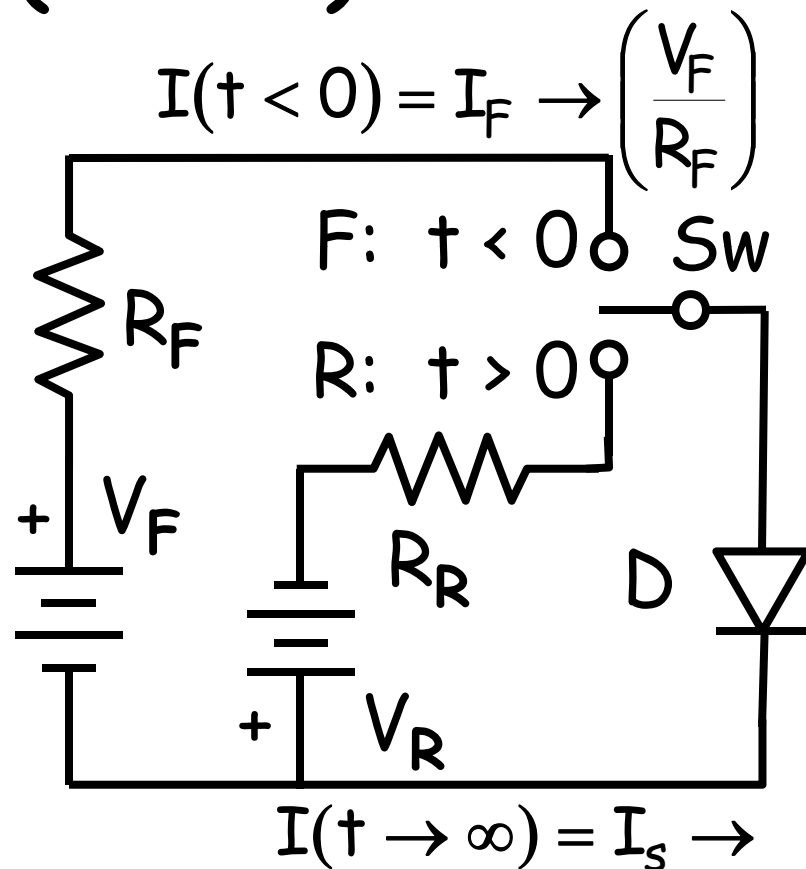
$$C_{depl} = C_j = C_{jo} \left( 1 - \frac{V_a}{V_{bi}} \right)^{-1/2}, V_a = V_Q$$



# Diode Switching

- Consider the charging and discharging of a Pn diode
  - $(N_a > N_d)$
  - $W_d \ll L_p$
  - For  $t < 0$ , apply the Thevenin pair  $V_F$  and  $R_F$ , so that in steady state
    - $I_F = (V_F - V_a)/R_F$ ,  $V_F \gg V_a$ , so current source
  - For  $t > 0$ , apply  $V_R$  and  $R_R$ 
    - $I_R = (V_R + V_a)/R_R$ ,  $V_R \gg V_a$ , so current source

# Diode switching (cont.)

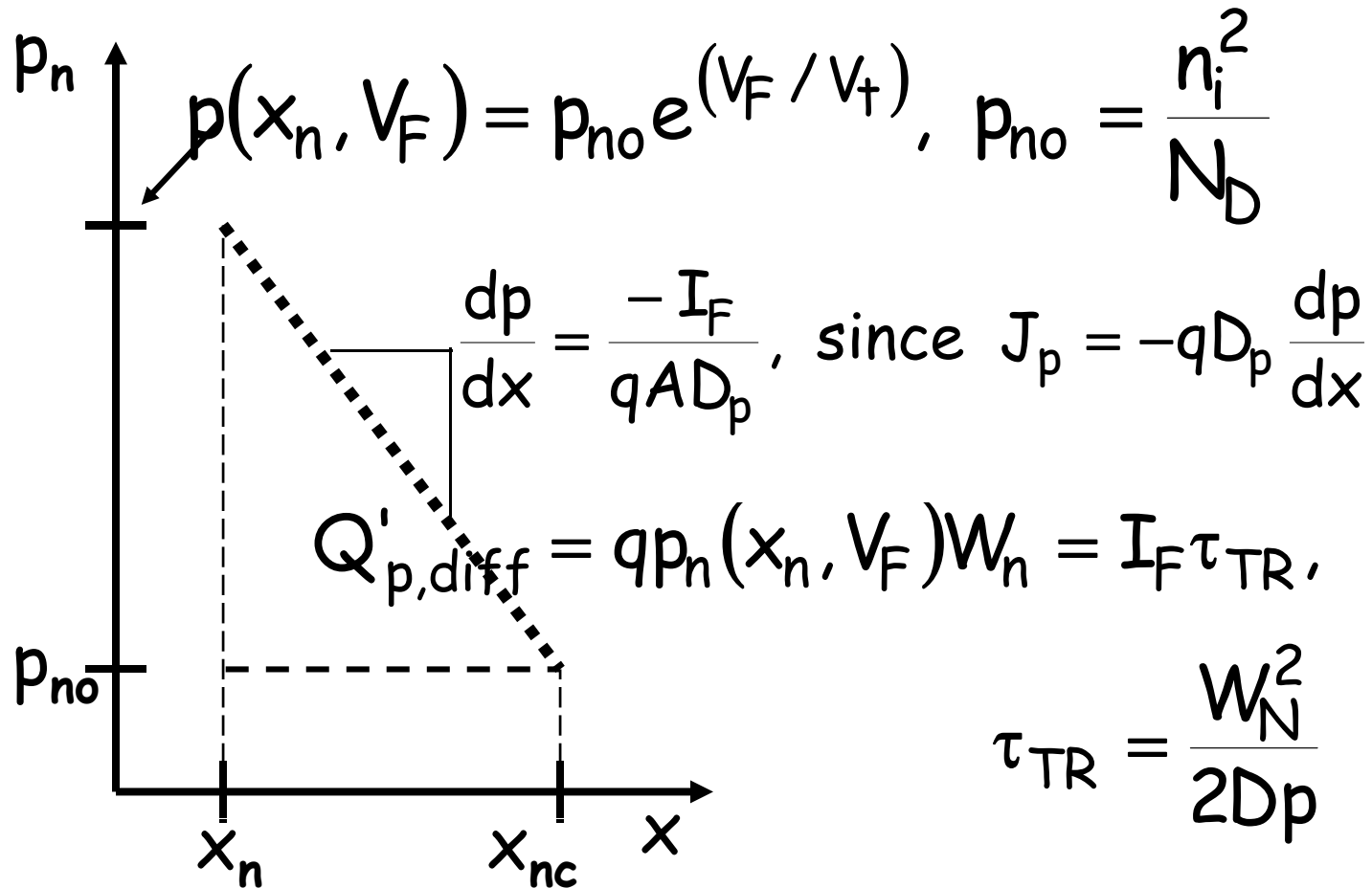


$$V_F, V_R \gg V_a$$

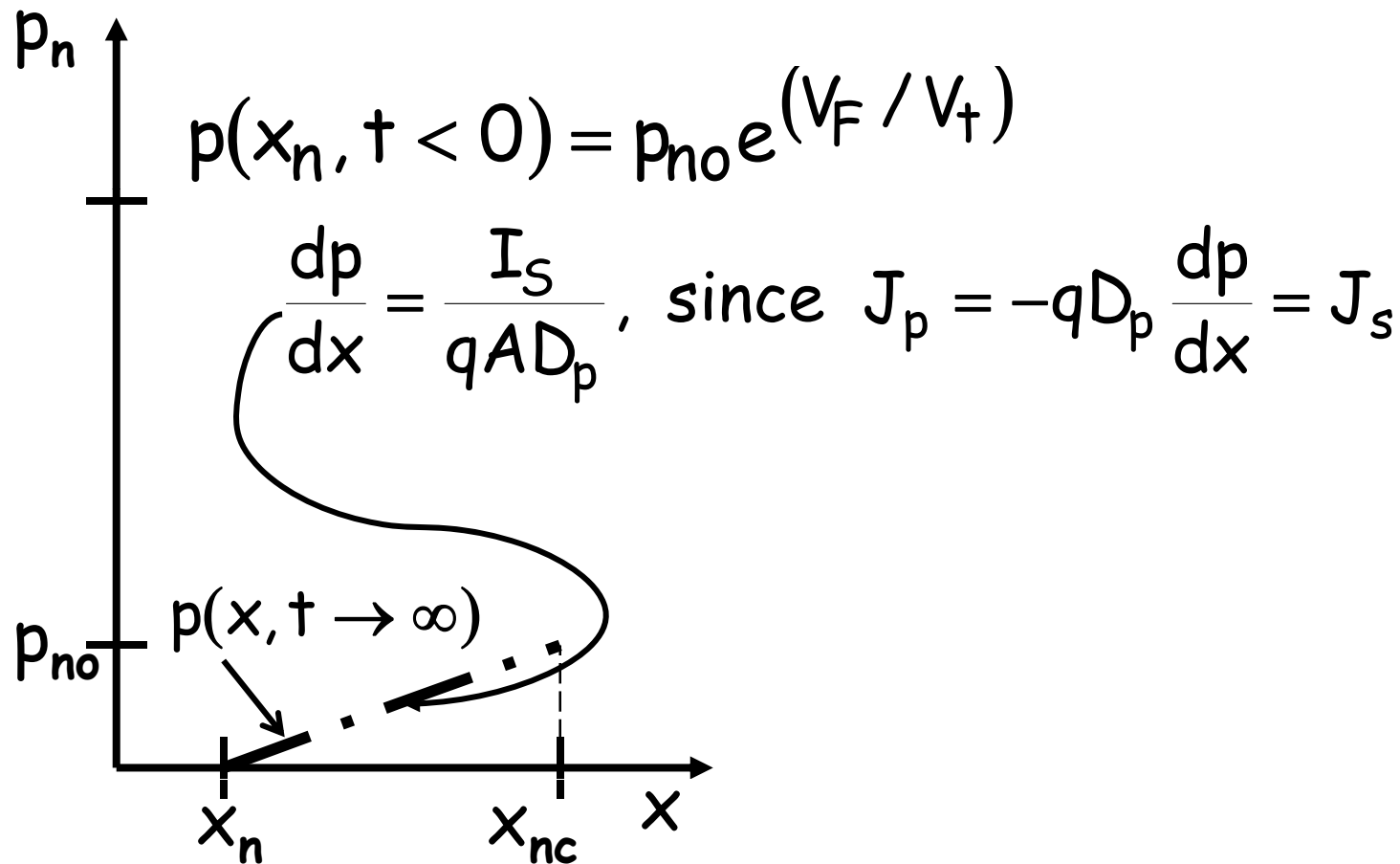
for  $t < 0$ ,

$$I_Q = \frac{V_F - V_a}{R_F} \approx \frac{V_F}{R_F}$$

# Diode charge for $t < 0$



# Diode charge for $t \gg \tau$ (long times)



# Equation

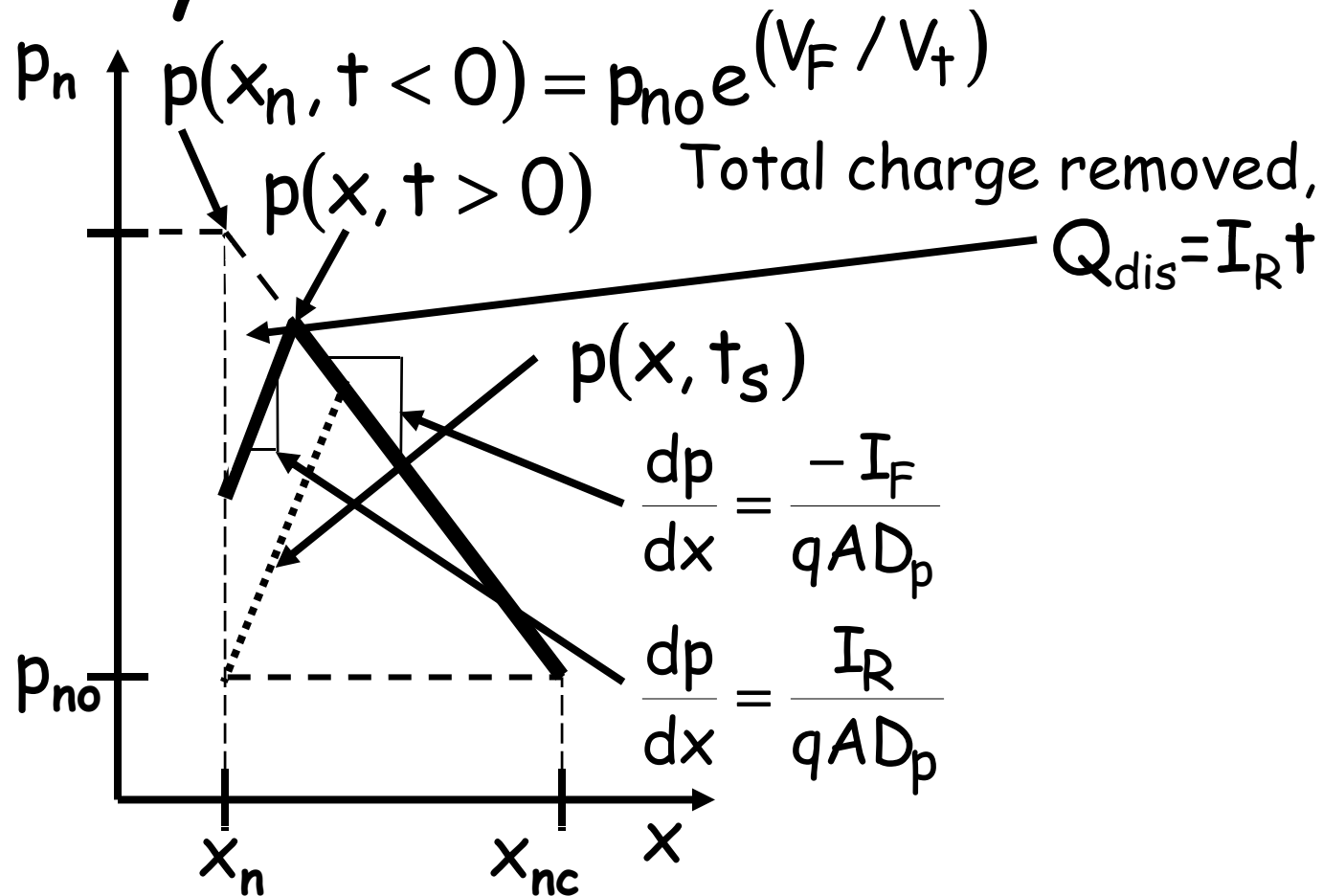
## summary

$$\frac{dp}{dx}\bigg|_{R, t \rightarrow \infty} = \frac{1}{qD_p} J_{p, \infty}$$
$$= \frac{I_s}{AqD_p}, \quad I_s = J_s A$$

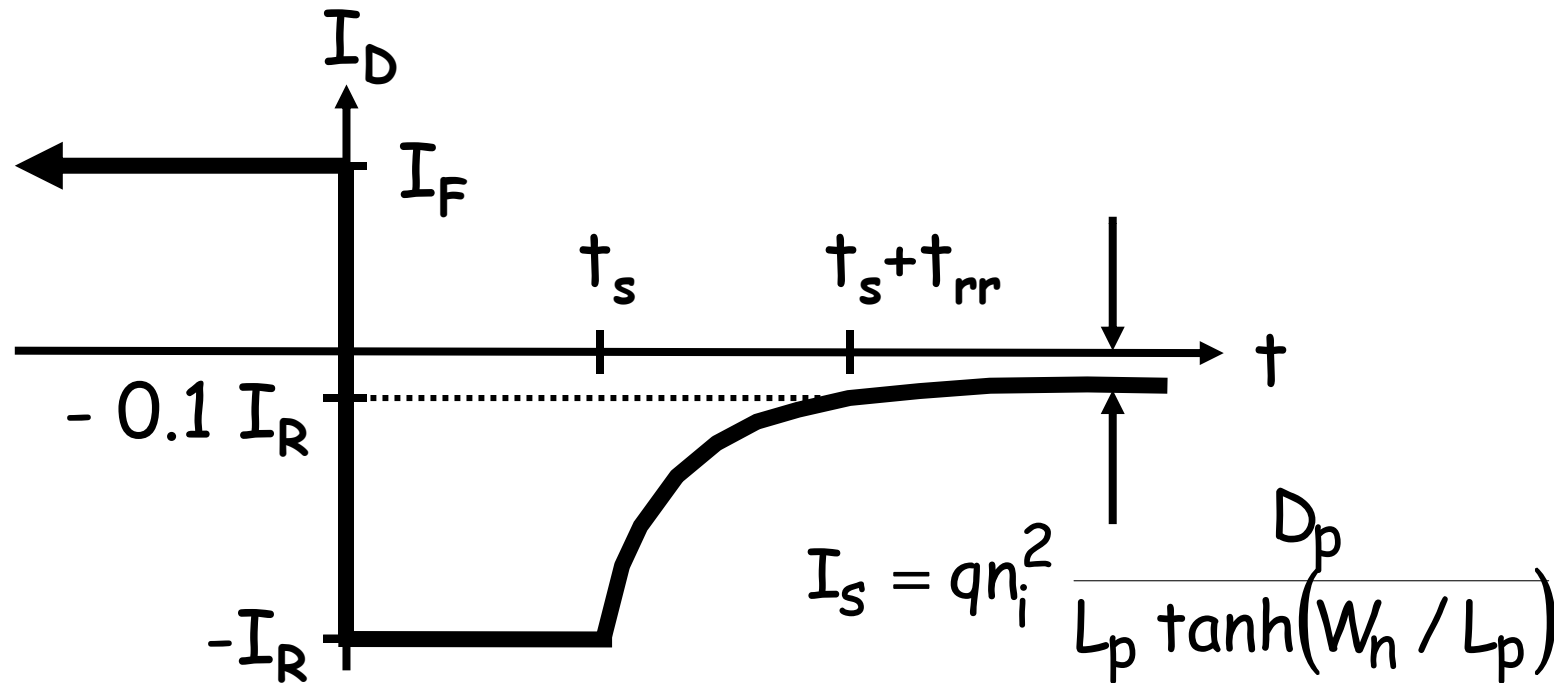
$$-\frac{dp}{dx}\bigg|_{F, t > 0} = \frac{I_F}{qAD_p}, \quad I_F = \frac{V_F}{R_F}$$

For  $t$  small, but  $> 0$ , a current,  $I_R \approx V_R / R_R$  flows to discharge  $Q$

# Snapshot for $t$ barely $> 0$

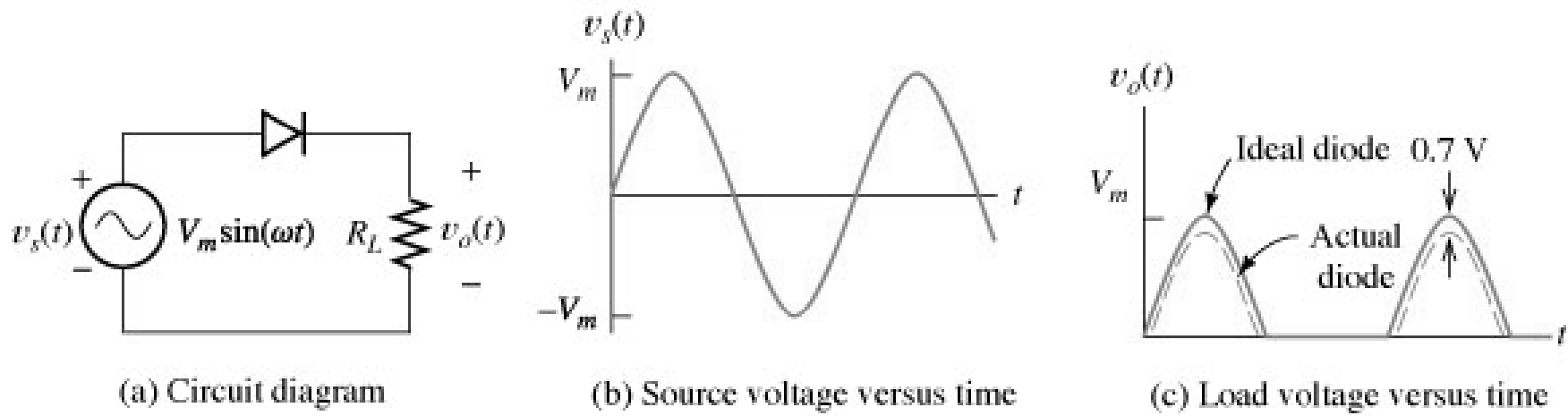


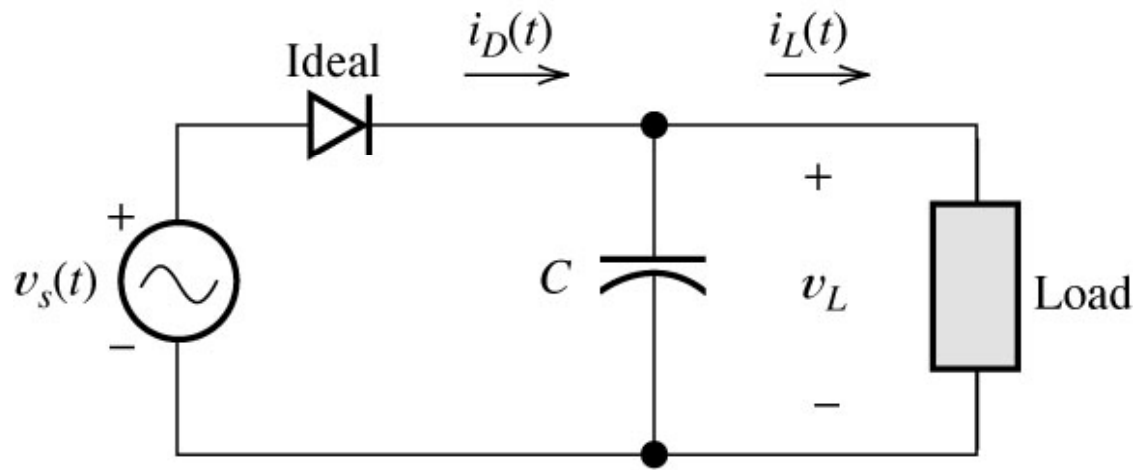
# I(t) for diode switching



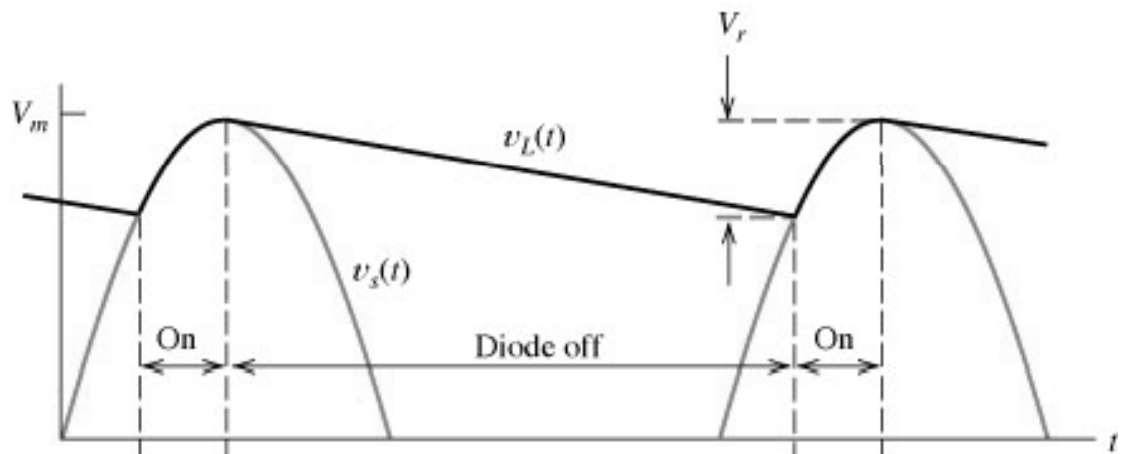
For  $0 < t < t_s$ ,  $\frac{dp}{dx} = \frac{I_R}{qAD_p}$  is a constant,

$$Q_{\text{discharge}} = I_R t_s$$

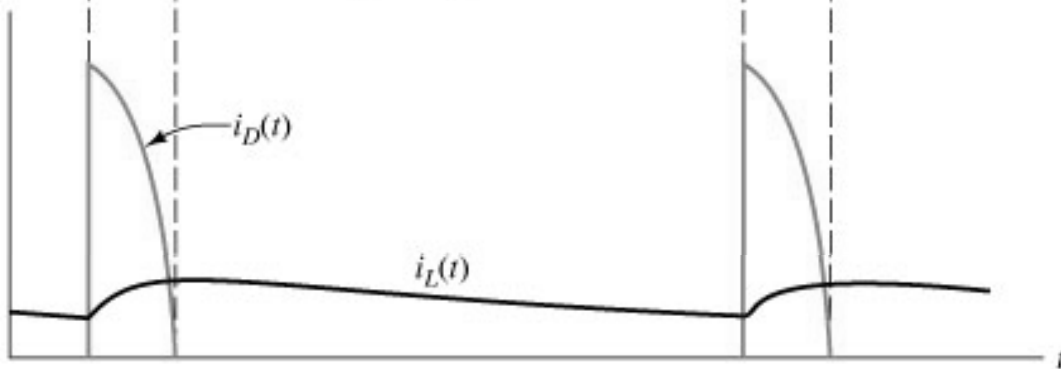




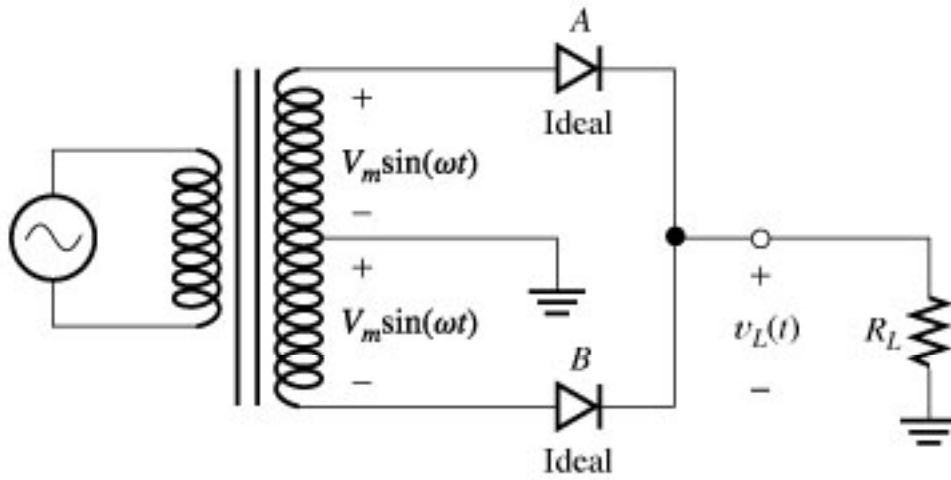
(a) Circuit diagram



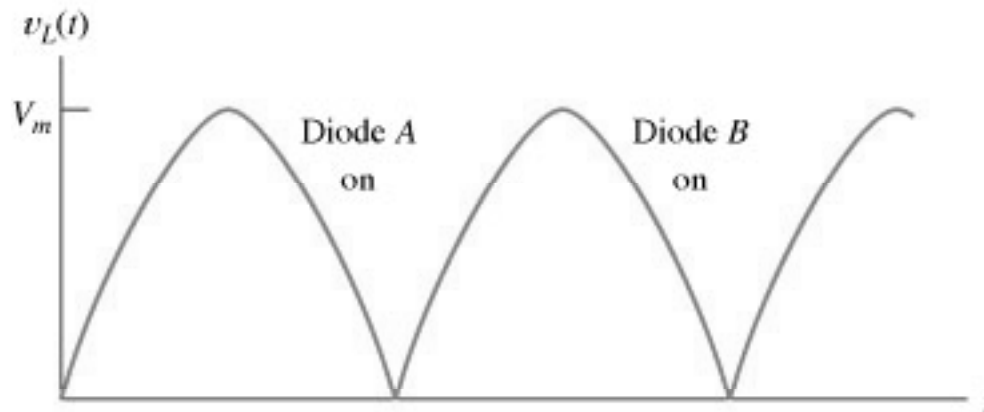
(b) Voltage waveforms



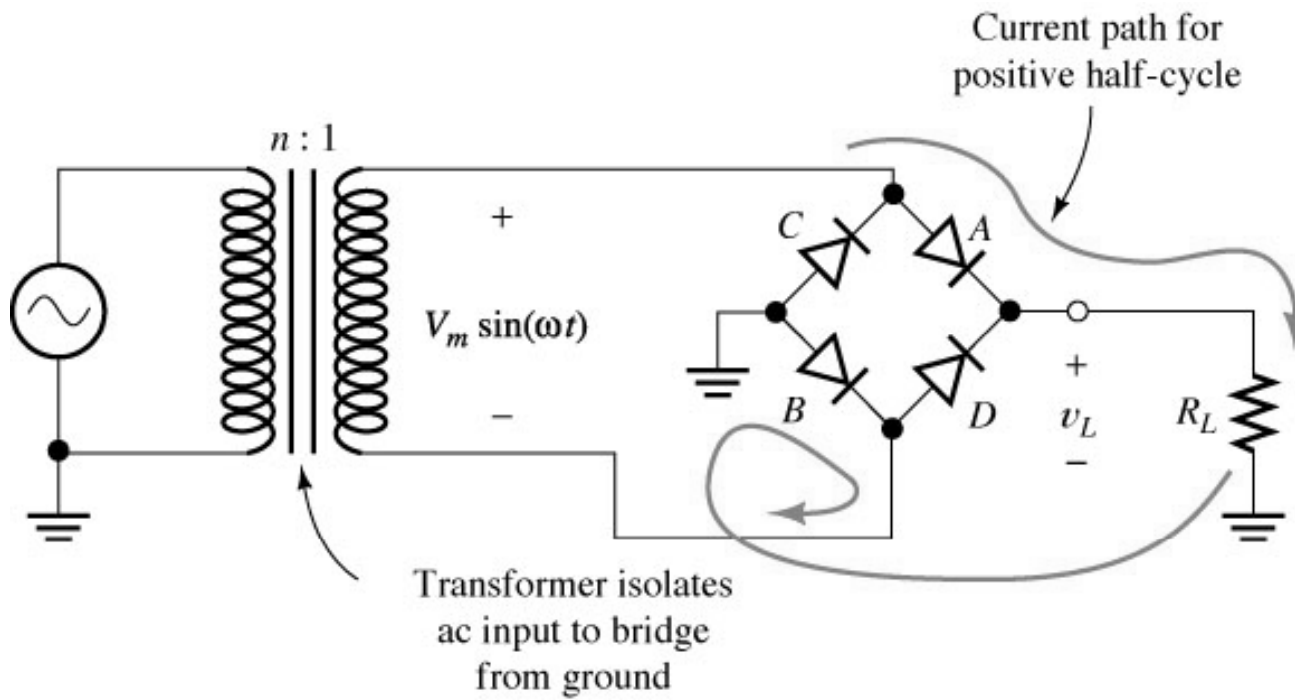
(c) Current waveforms



(a) Circuit diagram



(b) Output voltage



# References

- \* *Semiconductor Physics and Devices*, 2nd ed., by Neamen, Irwin, Boston, 1997.
- \*\* *Device Electronics for Integrated Circuits*, 2nd ed., by Muller and Kamins, John Wiley, New York, 1986.
- Where not otherwise noted, Figures not done by RLC are taken from:
  - *Electronics*, 2nd edition, by Allan R. Hambley, Prentice Hall, Upper Saddle River, NJ, © 2000.